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LV		<b>AA</b>	5,879,575	3,99	Tepman et al.					
		AB	5,868,353	2.99	Chen et al.					
		AC	5,830,279	11/98	Hackenberg					
		AD	5,817,578	10/98	Ogawa					
		AE	5,788,869	8/98	Daitos et al.					
		AF	5,756,400	5/98	Ye et al.				<del></del>	
		AG	5,681,424	10/97	Saito et al.					
		AH	5,679,215	10/97	Barnes et al.					
		AI	5,644,153	7/97	Keller	,				
		, L	5,626,775	5/97	Roberts et al.					
	)	AK	5,468,686	11/95	Kawamoto					
L	$\sqrt{}$	AL	5,780,338	7,98	Jeng et al.					
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1	AB	5,873,948	2/99	Kim					
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